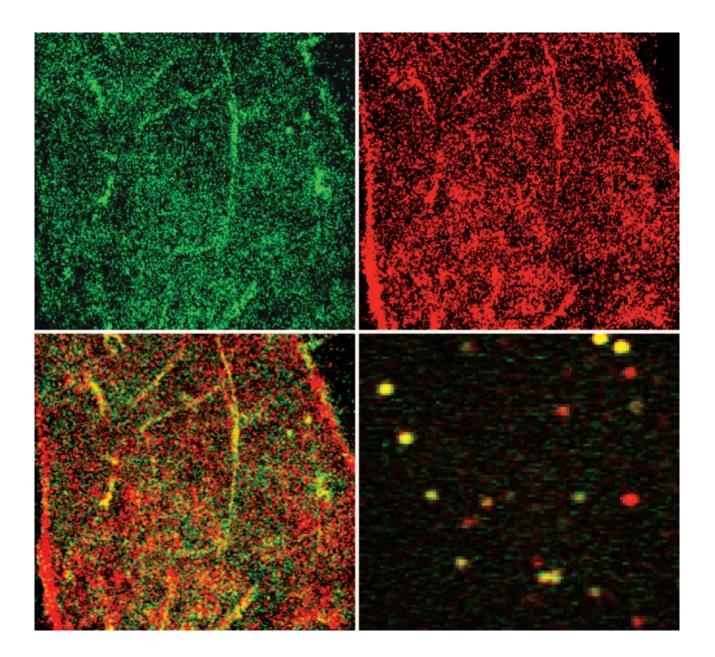
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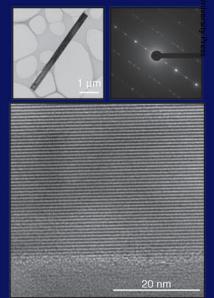




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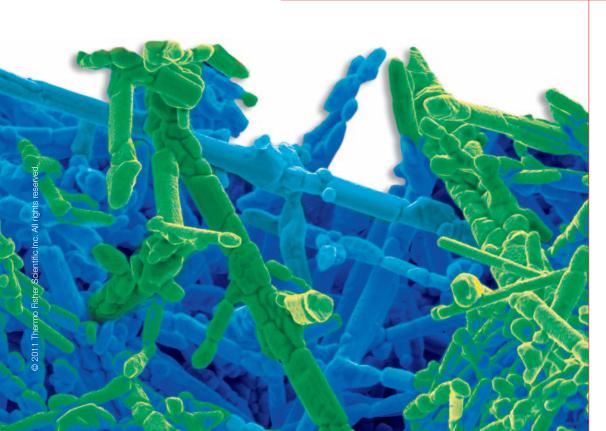


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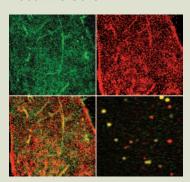
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Examples of two-color live-cell fluorescence photoactivation localization microscopy (FPALM). Image width for first three images = 11 μm; image width for lower right image = 12 μm.

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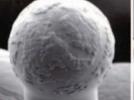
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